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DATE MAILED: 11/03/2004

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/083,684	02/27/2002	Tomonari Yamamoto	020254	1544
38834 75	590 11/03/2004		EXAM	INER
WESTERMAN, HATTORI, DANIELS & ADRIAN, LLP			ERDEM, FAZLI	
1250 CONNEC SUITE 700	TICUT AVENUE, NW		ART UNIT	PAPER NUMBER
	ON, DC 20036		2826	

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)
·		10/083,684	YAMAMOTO, TOMONARI
	Office Action Summary	Examiner	Art Unit
		Fazli Erdem	2826
eriod for	The MAILING DATE of this communication of Reply	appears on the cover sheet w	rith the correspondence address
THE M - Extens after S - If the p - If NO p - Failure Any re	PRTENED STATUTORY PERIOD FOR REI MAILING DATE OF THIS COMMUNICATION sions of time may be available under the provisions of 37 CFR IX (6) MONTHS from the mailing date of this communication. heriod for reply specified above is less than thirty (30) days, a bein of for reply is specified above, the maximum statutory perion to reply within the set or extended period for reply will, by staply received by the Office later than three months after the mail of patent term adjustment. See 37 CFR 1.704(b).	N. 1.136(a). In no event, however, may a reply within the statutory minimum of thio od will apply and will expire SIX (6) MOI tute, cause the application to become A	reply be timely filed rty (30) days will be considered timely. NTHS from the mailing date of this communication BANDONED (35 U.S.C. § 133).
tatus			
1) 🖂 F	Responsive to communication(s) filed on 06	6 August 2004.	
	· · · · —	his action is non-final.	
'—	Since this application is in condition for allow		ters, prosecution as to the merits is
-	closed in accordance with the practice unde	•	· •
	on of Claims		·
4) 🖂 (Claim(s) <u>1-4,6-10,12-14,16-19,21-23 and 2</u>	5-30 is/are nending in the an	polication.
	a) Of the above claim(s) is/are withd	•	phoadon.
	Claim(s) <u>1-4,6-10,12-14,16-19,21-23,25 and</u>		
_	Claim(s) 27-30 is/are rejected.		
7) 🗌 (Claim(s) is/are objected to.		
8) 🔲 (Claim(s) are subject to restriction and	d/or election requirement.	
pplicatio	on Papers		
9)□ T	he specification is objected to by the Exam	iner.	
	he drawing(s) filed on is/are: a)□ a		by the Examiner.
	Applicant may not request that any objection to t		
F	Replacement drawing sheet(s) including the corr	ection is required if the drawing	g(s) is objected to. See 37 CFR 1.121(d
11)□ T	he oath or declaration is objected to by the	Examiner. Note the attache	d Office Action or form PTO-152.
riority ur	nder 35 U.S.C. § 119		
	.cknowledgment is made of a claim for forei ☑ All b)	gn priority under 35 U.S.C.	§ 119(a)-(d) or (f).
1	I. Certified copies of the priority docume	ents have been received.	
2	2. Certified copies of the priority docume	ents have been received in A	Application No
	B. Copies of the certified copies of the p	riority documents have beer	received in this National Stage
3	application from the International Bure	201 (PCT Pulo 17 2/a))	
,	application from the international but	au (FC) Rule 17.2(a)).	

U.S. Patent and Trademark Office PTOL-326 (Rev. 1-04)

1) Notice of References Cited (PTO-892)

Paper No(s)/Mail Date _

2) Notice of Draftsperson's Patent Drawing Review (PTO-948)

3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)

4) Interview Summary (PTO-413)
Paper No(s)/Mail Date.

6) Other: ___

5) Notice of Informal Patent Application (PTO-152)

DETAILED ACTION

Allowable Subject Matter

1. Claims 1-4, 6-10, 12-14, 16-19, 21-23 25 and 26 allowed.

Claim Rejections - 35 USC § 103

- 2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 3. Claims 27 and 28 rejected under 35 U.S.C. 103(a) as being unpatentable over Talwar et al. (6,380,04) in view of Guegan (5,705,410).

Regarding Claims 27 and 28, Talwar et al. disclose a high speed semiconductor transsitor and selective absorption process forming same where in Fig. 1E, shallow source extension 60, shallow drain extension 62, deep source extension 80, deep drain extension 84 are formed under gate structure 36 and in single crystal 10. Source/drain extensions include dopants/impurities for amorphization. Talwar et al. fail to disclose the seeping of source/drain extension under the gate structure and the required capacitance value. However, Guegan disclose method of producing a semiconductor with a highly doped zone situated between lightly doped zones for the manufacture of transistors where in Fig. 2, source/drain extensions are under the gate and the required capacitance value is disclosed in column 7.

It would have been obvious to one of having ordinary skill in the art at the time the invention was made to include the required seeping of source/drain under the gate and

the required capacitance value in Talwar et al. as taught by Guegan in order to have a semiconductor structure with increased performance.

4. Claims 29 and 30 rejected under 35 U.S.C. 103(a) as being unpatentable over Talwar et al. (6,380,04) in view of Guegan (5,705,410) further in view of Chou et al. (5,308,780)

Regarding Claims 29 and 30, Talwar et al. disclose a high speed semiconductor transsitor and selective absorption process forming same where in Fig. 1E, shallow source extension 60, shallow drain extension 62, deep source extension 80, deep drain extension 84 are formed under gate structure 36 and in single crystal 10. Source/drain extensions include dopants/impurities for amorphization. Talwar et al. fail to disclose the seeping of source/drain extension under the gate structure, the required capacitance value, and the required larger tilt angle on one of the source/drain sides. However, Guegan disclose method of producing a semiconductor with a highly doped zone situated between lightly doped zones for the manufacture of transistors where in Fig. 2, source/drain extensions are under the gate and the required capacitance value is disclosed in column 7. Furthermore, Chou et al. disclose surface counter-doped N-LDD for high hot carrier reliability where in Fig. 3, larger tilt angle on one of the source/drain sides is disclosed.

It would have been obvious to one of having ordinary skill in the art at the time the invention was made to include the required seeping of source/drain under the gate, the required capacitance value, and the required larger tilt angle on one of the source/drain sides in Talwar et al. as taught by Guegan and Thou et al. respectively in order to have a semiconductor structure with increased performance.

Conclusion

Application/Control Number: 10/083,684

Art Unit: 2826

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Fazli Erdem whose telephone number is (571) 272-1914. The

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examiner can normally be reached on M - F 8:00 - 5:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Nathan Flynn can be reached on (571) 272-1915. The fax phone number for the

organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent

Application Information Retrieval (PAIR) system. Status information for published applications

may be obtained from either Private PAIR or Public PAIR. Status information for unpublished

applications is available through Private PAIR only. For more information about the PAIR

system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR

system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

FE

October 25, 2004